Supplementary data:

1. Cross section of the optical housing

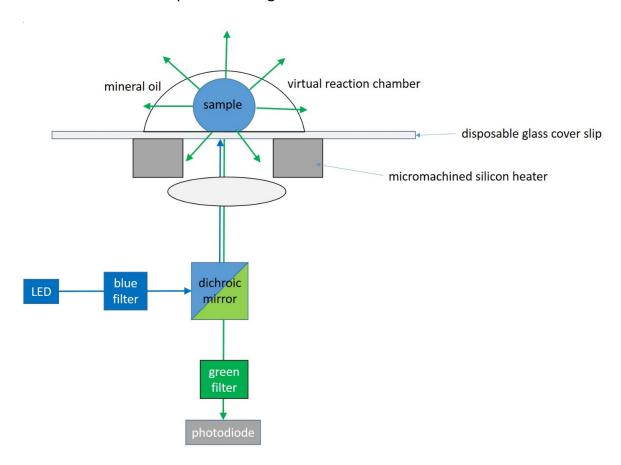


Figure 1: Cross section schematic of the handheld PCR system illustrating the optical path. Light emanating from the LEDs is filtered, then deflected by a dichroic mirror, and focused via lenses onto the VRC. A disposable glass slide separates the VRC from the micromachined silicon chip. The emitted fluorescence is collimated (using the same set of lenses), then passes through the dichroic mirror and a green filter prior to being captured by the photodiode.

2. Schematic of the PCR system

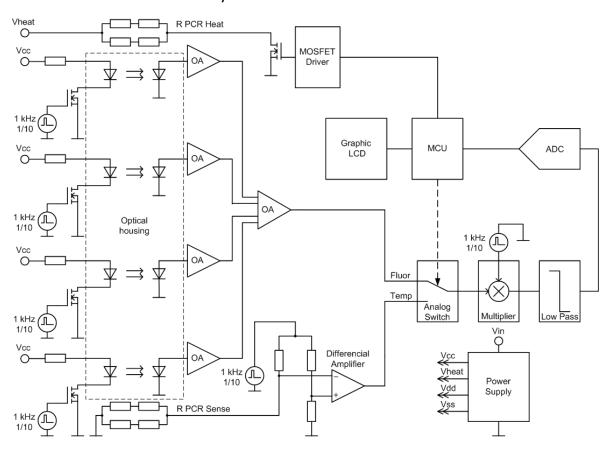


Figure 2: PCR electrical schematic showing four blocks of the fluorescent system inside the optical housing followed by transconductance operation amplifiers, by a generic amplifier and a Wheatstone bridge for temperature monitoring. The analog selector was used for further processing either the fluorescence or the temperature signals by the microcomputer (MCU) via an analog to digital converter (ADC). The processor also controls the dissipated Joule heat within the PCR chip and its temperature via a MOSFET driver.

3. List of components: Table 1

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$\begin{array}{c c} & \text{with } R_{DS(on)} = 170 \text{ m}\Omega \\ \\ \hline Power MOSFET & N-channel MOSFET & 1 \\ \hline with R_{DS(on)} = 30 \text{ m}\Omega \\ \\ \hline LED & Wavelength: 470 \text{ nm} & 4 \\ \hline Luminous intensity: \\ \hline 7.2-12 \text{ cd} \\ \hline Diameter: 5 \text{ mm} \\ \\ \end{array}$	
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	
LED Wavelength: 470 nm 4 Luminous intensity: 7.2 – 12 cd Diameter: 5 mm	
Luminous intensity: 7.2 – 12 cd Diameter: 5 mm	
7.2 – 12 cd Diameter: 5 mm	I
Diameter: 5 mm	
photodiode 7.4 mm ² 4	
Operation amplifier diFET with bias 4	
current < 100 fA	
Operation amplifier Noise < 15 nV/VHz @ 1	
1 kHz	
Differential amplifier Noise < 8 nV/VHz @ 1	
1 kHz	
Analog switch/analog 16 bit resolution, 2 1	
to digital converter selectable	
differential inputs	
Analog multiplier 4-quadrant analog 1	
multiplier	
Low pass filter 2 Hz cut off 1	
MCU 16 bit 1	
microprocessor	
Graphic display 84 × 42 pixels 1	
Switched power Generating DC 1	
supply voltages: +5V, ±12V,	
+18V	
thermomechanical Micromachined Custom layout, 1	
silicon chip integrated with thin	
film heater and RTD	
sensor	
optical Optical housing Made by CNC 1	
Low pass filter 490 nm 2	
Dichroic mirror 495 nm 2	
Long pass filter 510 nm 1	
Lens Diameter: 6.35 mm 4	
N.A.: 0.68	
Focal length: 3.1 mm	

4. PCR chip layout

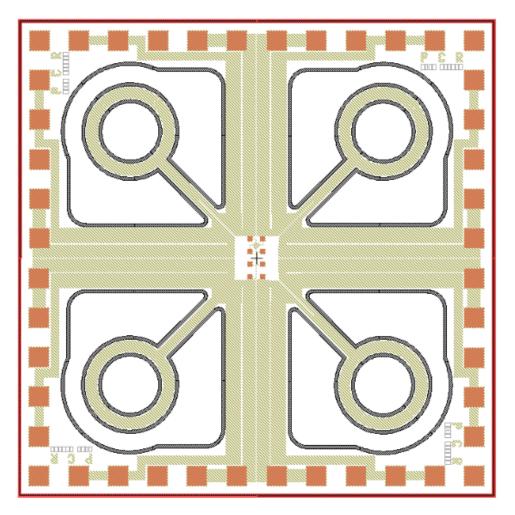


Figure 6 Layout of the PCR chip. The chip is square size with side of \approx 15 mm. The distance between heater centers is \approx 8mm.

- 5. PCR chip fabrication process
 - a. Starting substrate silicon wafers with diameter of ≈ 100 mm
 - b. SiO_2 deposition by plasma enhanced chemical vapor deposition (PECVD) process with thickness of $\approx 0.5 \ \mu m$
 - c. Au/Cr deposition by sputtering with thickness of \approx 200 nm and \approx 5 nm for Au and Cr, respectively
 - d. Contact lithography (Au/Cr patterning)
 - i. Positive photoresist (PR) spincoating with PR thickness between 1 and 2 μm
 - ii. PR pre-bake
 - iii. Soft contact exposure
 - iv. Postbake
 - v. PR developing
 - vi. Wafer spin drying
 - e. Au/Cr patterning by ion milling with secondary ion mass spectroscopy (SIMS) end point detection
 - f. PR removal by acetone and 2-n propyl alcohol or stripper
 - g. SiO_2 deposition by plasma enhanced chemical vapor deposition (PECVD) process with thickness of $\approx 0.5 \ \mu m$.
 - h. Contact lithography (bond pads opening)
 - i. PR spincoating with PR thickness between 1 μm and 2 μm
 - ii. PR pre-bake
 - iii. Soft contact exposure
 - iv. Postbake
 - v. PR developing
 - vi. Wafer spin drying
 - i. SiO₂ etching by $\approx 40 \%$ NH₄F and $\approx 49 \%$ HF in ratio of $\approx 7 : 1$ (BOE 7:1)
 - j. PR removal by acetone and 2-n propyl alcohol or stripper
 - k. Contact lithography (silicon etching)
 - i. PR spincoating with PR thickness between 8 and 12 μm
 - ii. PR pre-bake
 - iii. Soft contact exposure
 - iv. PR developing
 - v. Postbake
 - vi. Wafer spin drying
 - I. SiO₂ etching by BOE 7:1
 - m. Silicon etching by Bosch process through silicon water
 - n. PR removal by acetone and 2-n propyl alcohol or stripper
 - o. Chips drying by N₂
 - p. Soldering chips to the printed circuit boards